## Angle-resolved photoemission study of Bi<sub>2</sub>Sr<sub>1.6</sub>Ln<sub>0.4</sub>CuO<sub>6</sub> (Ln=La, Gd) with controlled out-of-plane disorder

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In high- $T_c$  cuprates, the effects of impurity or disorder have been widely discussed. The effects of Zn or Ni substitution in the CuO<sub>2</sub> plane have been studied by angle-resolved photoemission spectroscopy (ARPES) and the electronic structural change caused by the impurities has been revealed [1, 2]. Recently, in addition to the inplane disorder, the importance of out-of-plane disorder has been pointed out [3, 4]. The out-of-plane disorder reduces  $T_c$  as in the case of in-plane disorder. We have performed ARPES study of Bi<sub>2</sub>Sr<sub>1.6</sub>Ln<sub>0.4</sub>CuO<sub>6+d</sub> (Ln-Bi2201, Ln = La, Gd) with controlled out-of-plane disorder, where Gd-Bi2201 is much disordered than La-Bi2201, to reveal the effects of the disorder on the electronic structure.

The measured samples were optimally doped La-Bi2201 ( $T_c = 34$  K) and Gd-Bi2201 ( $T_c = 13$  K), which were prepared by the traveling solvent floating zone (TSFZ) method [3]. The ARPES measurements were performed at BL28A equipped with a SCIENTA SES2002 analyzer and a 5-axis *i*-gonio manipulator [5]. The photon energy was 50 eV. The total energy and angular resolution were set at ~15 meV and 0.3 degree, respectively. The measurement temperature was ~9 K. The samples were cleaved *in-situ* to obtain clean surfaces.



Fig. 1: *k*-space intensity plot of La-Bi2201. The open red circles and open blue squares show the Fermi surfaces of La-Bi2212 and Gd-Bi2212 determined from the MDC peak positions.

Figure 1 shows the *k*-space intensity plot for 20 meV around  $E_{\rm F}$  for La-Bi2201. The circles and the squares in the figure shows the Fermi surfaces determined from the MDC (momentum distribution curve) for La- and Gd-Bi2201, respectively. The shapes of the Fermi surface did not change with disorder, which means the hole concentration is exactly the same and suggest that the next-nearest-hopping integral t' did not change with disorder.



Fig. 2: MDC width along the nodal direction. The open circles are for La-Bi2201 and the open squares are for Gd-Bi2201.

Figure 2 shows the MDC at  $E_{\rm F}$  along the nodal (0, 0)-( $\pi$ ,  $\pi$ ) direction for La- and Gd-Bi2201. One can see the width of the MDC ( $\Delta_{\rm k}$ ) becomes larger with increasing disorder, which is due to the increase of the scattering of carriers by the disorder and is consistent with the results of the in-plane residual resistivity. The results suggest that the scattering in the nodal direction plays an important role in the depression of  $T_{\rm c}$ .

## **References**

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